

ABSTRACT OF THE DISCLOSURE

An apparatus for testing digital and analog signals from an integrated circuit includes an adder or subtractor 17 for being supplied with an analog signal outputted from the integrated circuit of a device under test and a signal outputted from a driver 11, an integrator 14 for being supplied with an analog signal outputted from the adder or subtractor 17, a switch 22 for selectively transmitting an analog signal outputted from the integrator 14 and a digital signal outputted from the integrated circuit to the comparator 13, and a switch 24 for selectively transmitting a signal outputted from a memory 20 and a signal outputted from a comparator 13 to the driver 11. At least one of the switches 22, 24 is operated depending on whether a signal to be tested is analog or digital.